# SINGLE 3-INPUT POSITIVE OR-AND GATE

**Check for Samples: SN74LVC1G3208-EP**

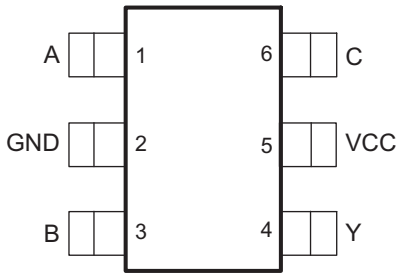
## FEATURES

- **Supports 5-V $V_{CC}$ Operation**
- **Inputs Accept Voltages to 5.5 V**
- **Max $t_{pd}$ of 5 ns at 3.3 V**
- **Low Power Consumption, 10-µA Max $I_{CC}$**
- **±24-mA Output Drive at 3.3 V**
- **Input Hysteresis Allows Slow Input Transition and Better Switching Noise Immunity at the Input ($V_{hys}$ = 250 mV Typ at 3.3 V)**
- **Can Be Used in Three Combinations:**
  - **OR-AND Gate**
  - **OR Gate**
  - **AND Gate**
- **$I_{off}$ Supports Partial-Power-Down Mode Operation**

## SUPPORTS DEFENSE, AEROSPACE, AND MEDICAL APPLICATIONS

- **Controlled Baseline**
- **One Assembly and Test Site**
- **One Fabrication Site**
- **Available in Military (-55°C to 125°C) Temperature Ranges** (1)
- **Extended Product Life Cycle**
- **Extended Product-Change Notification**
- **Product Traceability**

**DBV PACKAGE**
**(TOP VIEW)**




(1) Custom temperature ranges available

## DESCRIPTION/ORDERING INFORMATION

This device is designed for 1.65-V to 5.5-V $V_{CC}$ operation.

The SN74LVC1G3208 is a single 3-input positive OR-AND gate. It performs the Boolean function Y = (A + B) · C in positive logic.

By tying one input to GND or $V_{CC}$, the SN74LVC1G3208 offers two more functions. When C is tied to $V_{CC}$, this device performs as a 2-input OR gate (Y = A + B). When A is tied to GND, the device works as a 2-input AND gate (Y = B · C). This device also works as a 2-input AND gate when B is tied to GND (Y = A · C).

This device is fully specified for partial-power-down applications using $I_{off}$. The $I_{off}$ circuitry disables the outputs, preventing damaging current backflow through the device when it is powered down.

**Table 1. ORDERING INFORMATION(1)**

| $T_A$ | PACKAGE | | ORDERABLE PART NUMBER | TOP-SIDE MARKING | VID NUMBER |
|---|---|---|---|---|---|
| –55°C to 125°C | SOT (SOT-23) – DBV | Reel of 250 | 74LVC1G3208MDBVTEP | CDD5M | V62/13605-01XE |

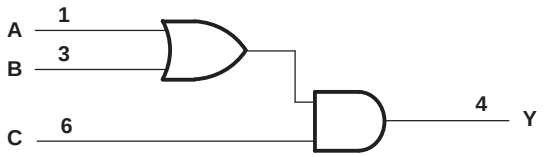
(1) For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI website at www.ti.com.

## FUNCTION TABLE(1)

| INPUTS | | | OUTPUT |
|---|---|---|---|
| A | B | C | Y |
| H | X | H | H |
| X | H | H | H |
| X | X | L | L |
| L | L | H | L |

(1) X = Valid H or L

## LOGIC DIAGRAM (POSITIVE LOGIC)




## FUNCTION SELECTION TABLE

| LOGIC FUNCTION | FIGURE |
|---|---|
| 2-Input AND Gate | 1 |
| 2-Input OR Gate | 2 |
| Y = (A + B) · C | 3 |

## LOGIC CONFIGURATIONS

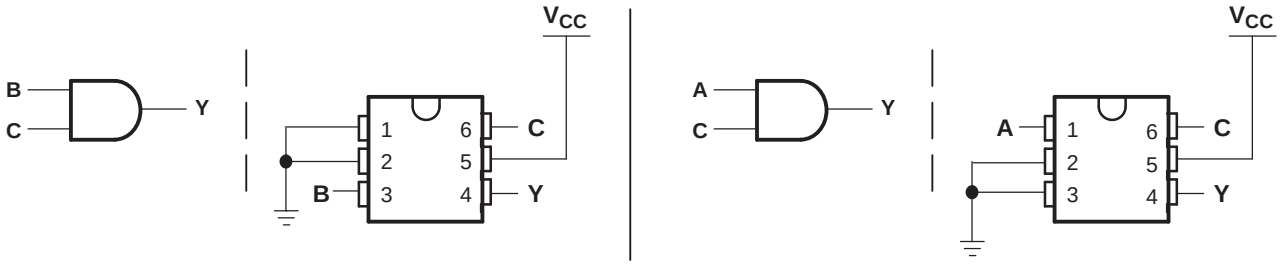



**Figure 1. 2-Input AND Gate**

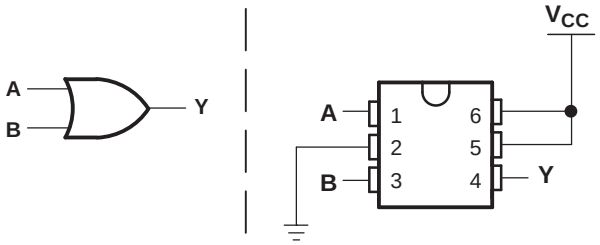



**Figure 2. 2-Input OR Gate**


**Figure 3. Y = (A + B) · C**

## Absolute Maximum Ratings(1)

over operating free-air temperature range (unless otherwise noted)

| | | | MIN | MAX | UNIT |
|---|---|---|---|---|---|
| $V_{CC}$ | Supply voltage range | | –0.5 | 6.5 | V |
| $V_I$ | Input voltage range(2) | | –0.5 | 6.5 | V |
| $V_O$ | Voltage range applied to any output in the high-impedance or power-off state(2) | | –0.5 | 6.5 | V |
| $V_O$ | Voltage range applied to any output in the high or low state(2) (3) | | –0.5 | $V_{CC}$ + 0.5 | V |
| $I_{IK}$ | Input clamp current | $V_I$ < 0 | | –50 | mA |
| $I_{OK}$ | Output clamp current | $V_O$ < 0 | | –50 | mA |
| $I_O$ | Continuous output current | | | ±50 | mA |
| | Continuous current through $V_{CC}$ or GND | | | ±100 | mA |
| $T_{stg}$ | Storage temperature range | | –65 | 150 | °C |

(1) Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
(2) The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
(3) The value of VCC is provided in the recommended operating conditions table.

## THERMAL INFORMATION

| THERMAL METRIC(1) | | SN74LVC1G3208 DBV 6 PINS | UNITS |
|---|---|---|---|
| $\theta_{JA}$ | Junction-to-ambient thermal resistance(2) | 207 | °C/W |
| $\theta_{JCtop}$ | Junction-to-case (top) thermal resistance(3) | 148.1 | |
| $\theta_{JB}$ | Junction-to-board thermal resistance(4) | 50.6 | |
| $\psi_{JT}$ | Junction-to-top characterization parameter(5) | 41.2 | |
| $\psi_{JB}$ | Junction-to-board characterization parameter(6) | 50.1 | |
| $\theta_{JCbot}$ | Junction-to-case (bottom) thermal resistance(7) | N/A | |

(1) For more information about traditional and new thermal metrics, see the *IC Package Thermal Metrics* application report, SPRA953.
(2) The junction-to-ambient thermal resistance under natural convection is obtained in a simulation on a JEDEC-standard, high-K board, as specified in JESD51-7, in an environment described in JESD51-2a.
(3) The junction-to-case (top) thermal resistance is obtained by simulating a cold plate test on the package top. No specific JEDEC-standard test exists, but a close description can be found in the ANSI SEMI standard G30-88.
(4) The junction-to-board thermal resistance is obtained by simulating in an environment with a ring cold plate fixture to control the PCB temperature, as described in JESD51-8.
(5) The junction-to-top characterization parameter, $\psi_{JT}$, estimates the junction temperature of a device in a real system and is extracted from the simulation data for obtaining $\theta_{JA}$, using a procedure described in JESD51-2a (sections 6 and 7).
(6) The junction-to-board characterization parameter, $\psi_{JB}$, estimates the junction temperature of a device in a real system and is extracted from the simulation data for obtaining $\theta_{JA}$ , using a procedure described in JESD51-2a (sections 6 and 7).
(7) The junction-to-case (bottom) thermal resistance is obtained by simulating a cold plate test on the exposed (power) pad. No specific JEDEC standard test exists, but a close description can be found in the ANSI SEMI standard G30-88.

## Recommended Operating Conditions(1)

| | | | MIN | MAX | UNIT |
|---|---|---|---|---|---|
| $V_{CC}$ | Supply voltage | Operating | 1.65 | 5.5 | V |
| | | Data retention only | 1.5 | | |
| $V_{IH}$ | High-level input voltage | $V_{CC}$ = 1.65 V to 1.95 V | 0.65 × $V_{CC}$ | | V |
| | | $V_{CC}$ = 2.3 V to 2.7 V | 1.7 | | |
| | | $V_{CC}$ = 3 V to 3.6 V | 2 | | |
| | | $V_{CC}$ = 4.5 V to 5.5 V | 0.7 × $V_{CC}$ | | |
| $V_{IL}$ | Low-level input voltage | $V_{CC}$ = 1.65 V to 1.95 V | | 0.35 × $V_{CC}$ | V |
| | | $V_{CC}$ = 2.3 V to 2.7 V | | 0.7 | |
| | | $V_{CC}$ = 3 V to 3.6 V | | 0.8 | |
| | | $V_{CC}$ = 4.5 V to 5.5 V | | 0.3 × $V_{CC}$ | |
| $V_I$ | Input voltage | | 0 | 5.5 | V |
| $V_O$ | Output voltage | | 0 | $V_{CC}$ | V |
| $I_{OH}$ | High-level output current | $V_{CC}$ = 1.65 V | | –4 | mA |
| | | $V_{CC}$ = 2.3 V | | –8 | |
| | | $V_{CC}$ = 3 V | | –16 | |
| | | | | –24 | |
| | | $V_{CC}$ = 4.5 V | | –32 | |
| $I_{OL}$ | Low-level output current | $V_{CC}$ = 1.65 V | | 4 | mA |
| | | $V_{CC}$ = 2.3 V | | 8 | |
| | | $V_{CC}$ = 3 V | | 16 | |
| | | | | 24 | |
| | | $V_{CC}$ = 4.5 V | | 32 | |
| Δt/Δv | Input transition rise or fall rate | $V_{CC}$ = 1.8 V ± 0.15 V, 2.5 V ± 0.2 V | | 20 | ns/V |
| | | $V_{CC}$ = 3.3 V ± 0.3 V | | 10 | |
| | | $V_{CC}$ = 5 V ± 0.5 V | | 5 | |
| $T_A$ | Operating free-air temperature | | –55 | 125 | °C |

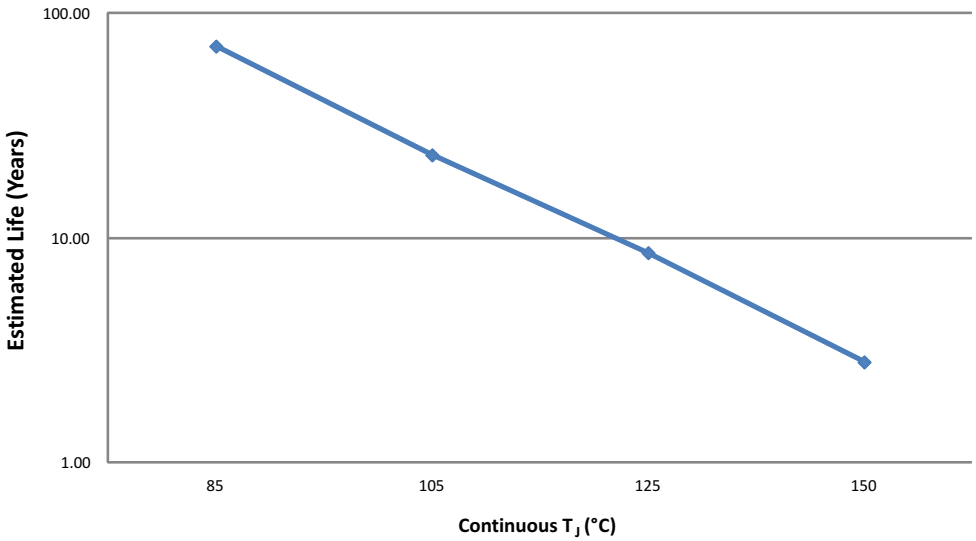
(1) All unused inputs of the device must be held at $V_{CC}$ or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

## Electrical Characteristics

over recommended operating free-air temperature range (unless otherwise noted)

| PARAMETER | | TEST CONDITIONS | | $V_{CC}$ | MIN | TYP(1) | MAX | UNIT |
|---|---|---|---|---|---|---|---|---|
| $V_{OH}$ | | $I_{OH}$ = –100 µA | | 1.65 V to 5.5 V | $V_{CC}$ – 0.1 | | | V |
| | | $I_{OH}$ = –4 mA | | 1.65 V | 1.2 | | | |
| | | $I_{OH}$ = –8 mA | | 2.3 V | 1.9 | | | |
| | | $I_{OH}$ = –16 mA | | 3 V | 2.4 | | | |
| | | $I_{OH}$ = –24 mA | | | 2.3 | | | |
| | | $I_{OH}$ = –32 mA | | 4.5 V | 3.8 | | | |
| $V_{OL}$ | | $I_{OL}$ = 100 µA | | 1.65 V to 5.5 V | | | 0.11 | V |
| | | $I_{OL}$ = 4 mA | | 1.65 V | | | 0.52 | |
| | | $I_{OL}$ = 8 mA | | 2.3 V | | | 0.45 | |
| | | $I_{OL}$ = 16 mA | | 3 V | | | 0.68 | |
| | | $I_{OL}$ = 24 mA | | | | | 1.1 | |
| | | $I_{OL}$ = 32 mA | | 4.5 V | | | 1.1 | |
| $I_I$ | A, B, or C inputs | $V_I$ = 5.5 V or GND | | 0 to 5.5 V | -12.05 | | 8.6 | µA |
| $I_{off}$ | | $V_I$ or $V_O$ = 5.5 V | | 0 | -22 | | 41.5 | µA |
| $I_{CC}$ | | $V_I$ = 5.5 V or GND | $I_O$ = 0 | 1.65 V to 5.5 V | | | 12.5 | µA |
| $\Delta I_{CC}$ | | One input at $V_{CC}$ – 0.6 V, | Other inputs at $V_{CC}$ or GND | 3 V to 5.5 V | | | 500 | µA |
| $C_i$ | | $V_I$ = $V_{CC}$ or GND | | 3.3 V | | 3.5 | | pF |

(1) All typical values are at $V_{CC}$ = 3.3 V, $T_A$ = 25°C.




(1) See datasheet for absolute maximum and minimum recommended operating conditions.

(2) Silicon operating life design goal is 10 years at 105°C junction temperature (does not include package interconnect life).

(3) Enhanced plastic product disclaimer applies.

**Figure 4. Electromigration Fail Mode/Wirebond Life Derating Chart**

## Switching Characteristics

over recommended operating free-air temperature range, $C_L$ = 15 pF (unless otherwise noted) (see Figure 5)

| PARAMETER | FROM (INPUT) | TO (OUTPUT) | $V_{CC}$ = 1.8 V ± 0.15 V | | $V_{CC}$ = 2.5 V ± 0.2 V | | $V_{CC}$ = 3.3 V ± 0.3 V | | $V_{CC}$ = 5 V ± 0.5 V | | UNIT |
|---|---|---|---|---|---|---|---|---|---|---|---|
| | | | MIN | MAX | MIN | MAX | MIN | MAX | MIN | MAX | |
| $t_{pd}$ | A, B, or C | Y | 3.7 | 14 | 2.5 | 7 | 1.7 | 5 | 1.3 | 3.4 | ns |

## Switching Characteristics

over recommended operating free-air temperature range, $C_L$ = 30 pF or 50 pF (unless otherwise noted) (see Figure 6)

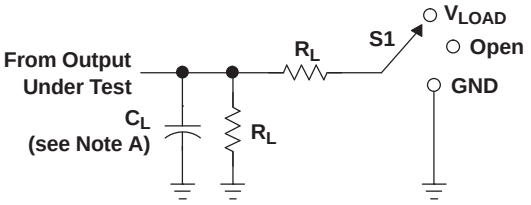
| PARAMETER | FROM (INPUT) | TO (OUTPUT) | $V_{CC}$ = 1.8 V ± 0.15 V | | $V_{CC}$ = 2.5 V ± 0.2 V | | $V_{CC}$ = 3.3 V ± 0.3 V | | $V_{CC}$ = 5 V ± 0.5 V | | UNIT |
|---|---|---|---|---|---|---|---|---|---|---|---|
| | | | MIN | MAX | MIN | MAX | MIN | MAX | MIN | MAX | |
| $t_{pd}$ | A, B, or C | Y | 2.5 | 17.5 | 1.8 | 7.6 | 1.8 | 5.9 | 0.8 | 4.5 | ns |

## Operating Characteristics

$T_A$ = 25°C

| PARAMETER | | TEST CONDITIONS | $V_{CC}$ = 1.8 V | $V_{CC}$ = 2.5 V | $V_{CC}$ = 3.3 V | $V_{CC}$ = 5 V | UNIT |
|---|---|---|---|---|---|---|---|
| | | | TYP | TYP | TYP | TYP | |
| $C_{pd}$ | Power dissipation capacitance | f = 10 MHz | 15 | 15 | 16 | 17 | pF |

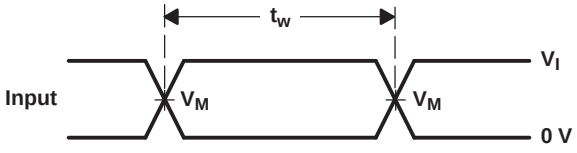
## PARAMETER MEASUREMENT INFORMATION



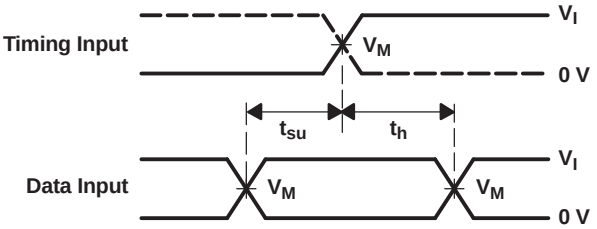

LOAD CIRCUIT

| TEST | S1 |
|---|---|
| $t_{PLH}/t_{PHL}$ | Open |
| $t_{PLZ}/t_{PZL}$ | $V_{LOAD}$ |
| $t_{PHZ}/t_{PZH}$ | GND |

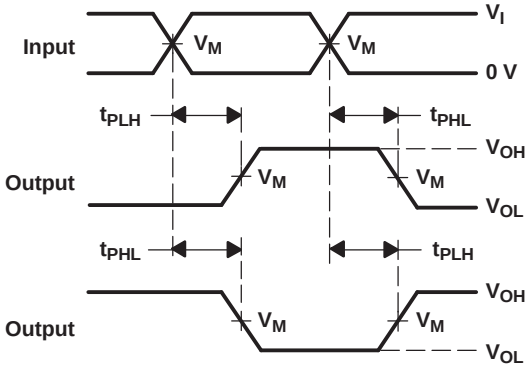
| $V_{CC}$ | INPUTS | | $V_M$ | $V_{LOAD}$ | $C_L$ | $R_L$ | $V_\Delta$ |
|---|---|---|---|---|---|---|---|
| | $V_I$ | $t_r/t_f$ | | | | | |
| 1.8 V ± 0.15 V | $V_{CC}$ | ≤2 ns | $V_{CC}/2$ | $2 \times V_{CC}$ | 15 pF | 1 MΩ | 0.15 V |
| 2.5 V ± 0.2 V | $V_{CC}$ | ≤2 ns | $V_{CC}/2$ | $2 \times V_{CC}$ | 15 pF | 1 MΩ | 0.15 V |
| 3.3 V ± 0.3 V | 3 V | ≤2.5 ns | 1.5 V | 6 V | 15 pF | 1 MΩ | 0.3 V |
| 5 V ± 0.5 V | $V_{CC}$ | ≤2.5 ns | $V_{CC}/2$ | $2 \times V_{CC}$ | 15 pF | 1 MΩ | 0.3 V |



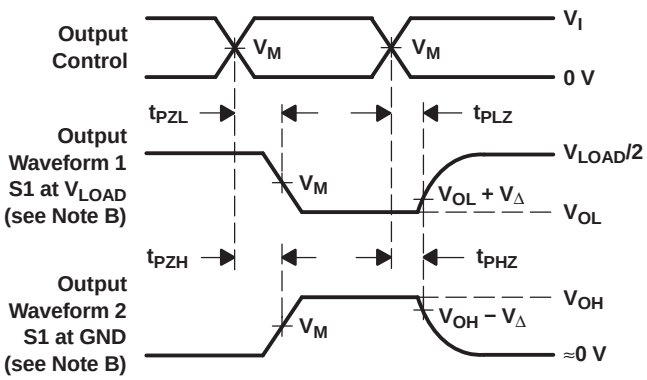

VOLTAGE WAVEFORMS
PULSE DURATION




VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES




VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES
INVERTING AND NONINVERTING OUTPUTS

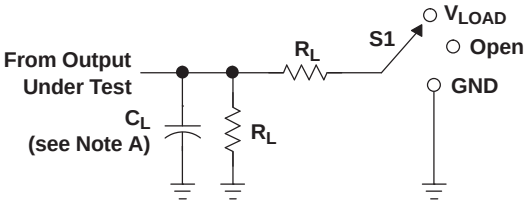



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES
LOW- AND HIGH-LEVEL ENABLING

NOTES:
A. $C_L$ includes probe and jig capacitance.
B. Waveform 1 is for an output with internal conditions such that the output is low, except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high, except when disabled by the output control.
C. All input pulses are supplied by generators having the following characteristics: PRR ≤ 10 MHz, $Z_O$ = 50 Ω.
D. The outputs are measured one at a time, with one transition per measurement.
E. $t_{PLZ}$ and $t_{PHZ}$ are the same as $t_{dis}$.
F. $t_{PZL}$ and $t_{PZH}$ are the same as $t_{en}$.
G. $t_{PLH}$ and $t_{PHL}$ are the same as $t_{pd}$.
H. All parameters and waveforms are not applicable to all devices.

**Figure 5. Load Circuit and Voltage Waveforms**

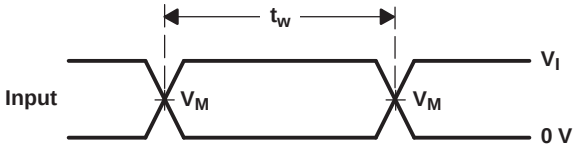
## PARAMETER MEASUREMENT INFORMATION



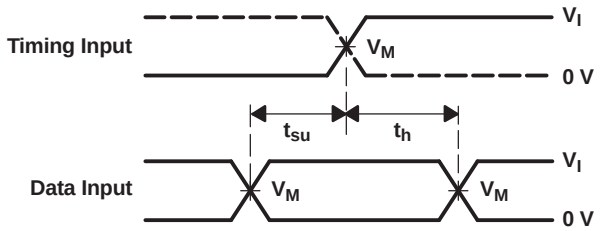

LOAD CIRCUIT

| TEST | S1 |
|---|---|
| $t_{PLH}/t_{PHL}$ | Open |
| $t_{PLZ}/t_{PZL}$ | $V_{LOAD}$ |
| $t_{PHZ}/t_{PZH}$ | GND |

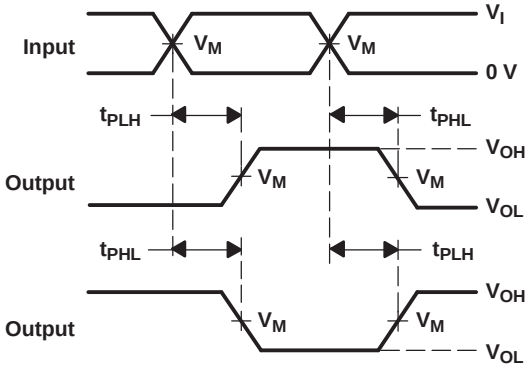
| $V_{CC}$ | INPUTS | | $V_M$ | $V_{LOAD}$ | $C_L$ | $R_L$ | $V_\Delta$ |
|---|---|---|---|---|---|---|---|
| | $V_I$ | $t_r/t_f$ | | | | | |
| 1.8 V ± 0.15 V | $V_{CC}$ | ≤2 ns | $V_{CC}/2$ | $2 \times V_{CC}$ | 30 pF | 1 kΩ | 0.15 V |
| 2.5 V ± 0.2 V | $V_{CC}$ | ≤2 ns | $V_{CC}/2$ | $2 \times V_{CC}$ | 30 pF | 500 Ω | 0.15 V |
| 3.3 V ± 0.3 V | 3 V | ≤2.5 ns | 1.5 V | 6 V | 50 pF | 500 Ω | 0.3 V |
| 5 V ± 0.5 V | $V_{CC}$ | ≤2.5 ns | $V_{CC}/2$ | $2 \times V_{CC}$ | 50 pF | 500 Ω | 0.3 V |



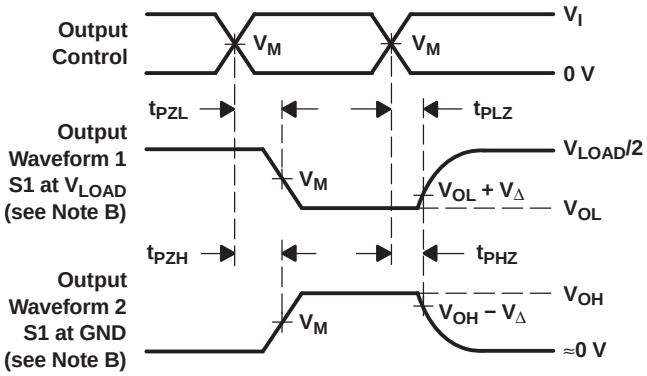

VOLTAGE WAVEFORMS
PULSE DURATION




VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES




VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES
INVERTING AND NONINVERTING OUTPUTS




VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES
LOW- AND HIGH-LEVEL ENABLING

NOTES:
A. $C_L$ includes probe and jig capacitance.
B. Waveform 1 is for an output with internal conditions such that the output is low, except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high, except when disabled by the output control.
C. All input pulses are supplied by generators having the following characteristics: PRR ≤ 10 MHz, $Z_O$ = 50 Ω.
D. The outputs are measured one at a time, with one transition per measurement.
E. $t_{PLZ}$ and $t_{PHZ}$ are the same as $t_{dis}$.
F. $t_{PZL}$ and $t_{PZH}$ are the same as $t_{en}$.
G. $t_{PLH}$ and $t_{PHL}$ are the same as $t_{pd}$.
H. All parameters and waveforms are not applicable to all devices.

**Figure 6. Load Circuit and Voltage Waveforms**

## PACKAGING INFORMATION

| Orderable Device | Status (1) | Package Type | Package Drawing | Pins | Package Qty | Eco Plan (2) | Lead/Ball Finish | MSL Peak Temp (3) | Op Temp (°C) | Top-Side Markings (4) | Samples |
|---|---|---|---|---|---|---|---|---|---|---|---|
| 74LVC1G3208MDBVTEP | PREVIEW | SOT-23 | DBV | 6 | 250 | Green (RoHS & no Sb/Br) | CU NIPDAU | Level-1-260C-UNLIM | -55 to 125 | | |

(1) The marketing status values are defined as follows:
**ACTIVE:** Product device recommended for new designs.
**LIFEBUY:** TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.
**NRND:** Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.
**PREVIEW:** Device has been announced but is not in production. Samples may or may not be available.
**OBSOLETE:** TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.
**TBD:** The Pb-Free/Green conversion plan has not been defined.
**Pb-Free (RoHS):** TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.
**Pb-Free (RoHS Exempt):** This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.
**Green (RoHS & no Sb/Br):** TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

(3) MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

(4) Only one of markings shown within the brackets will appear on the physical device.



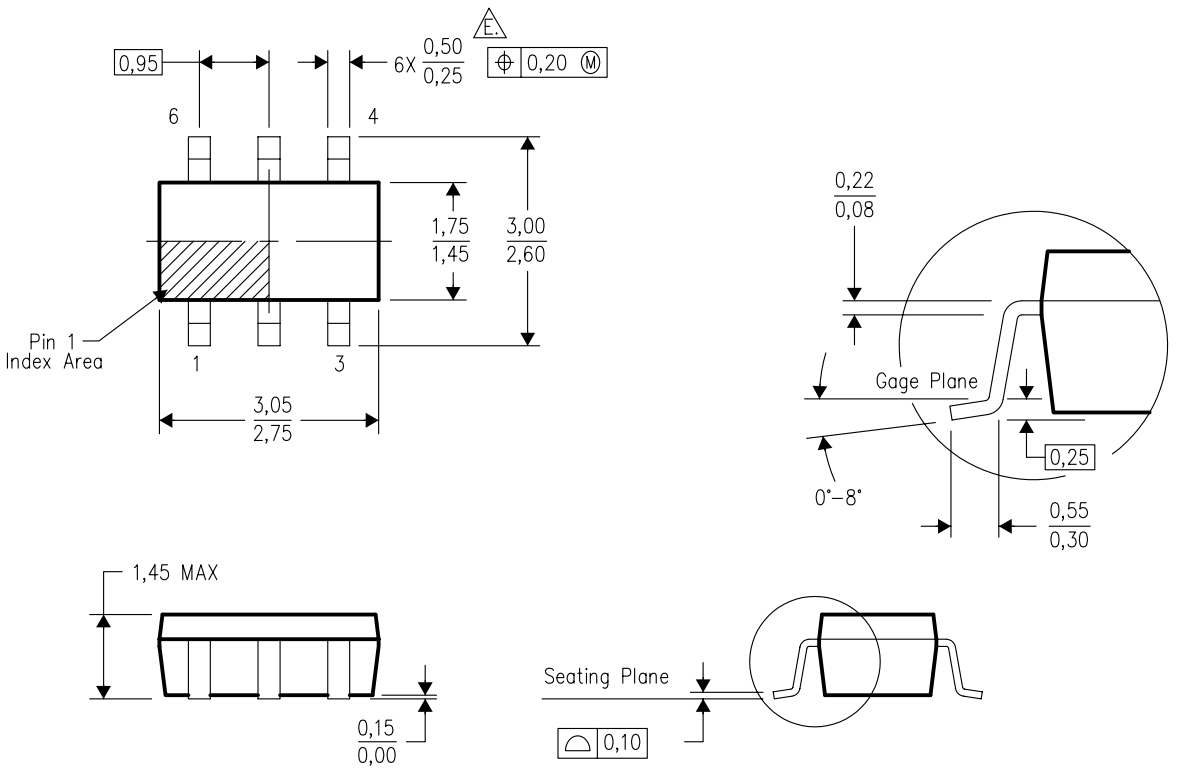
**OTHER QUALIFIED VERSIONS OF SN74LVC1G3208-EP :**

- Catalog: SN74LVC1G3208
- Automotive: SN74LVC1G3208-Q1

NOTE: Qualified Version Definitions:

- Catalog - TI's standard catalog product
- Automotive - Q100 devices qualified for high-reliability automotive applications targeting zero defects

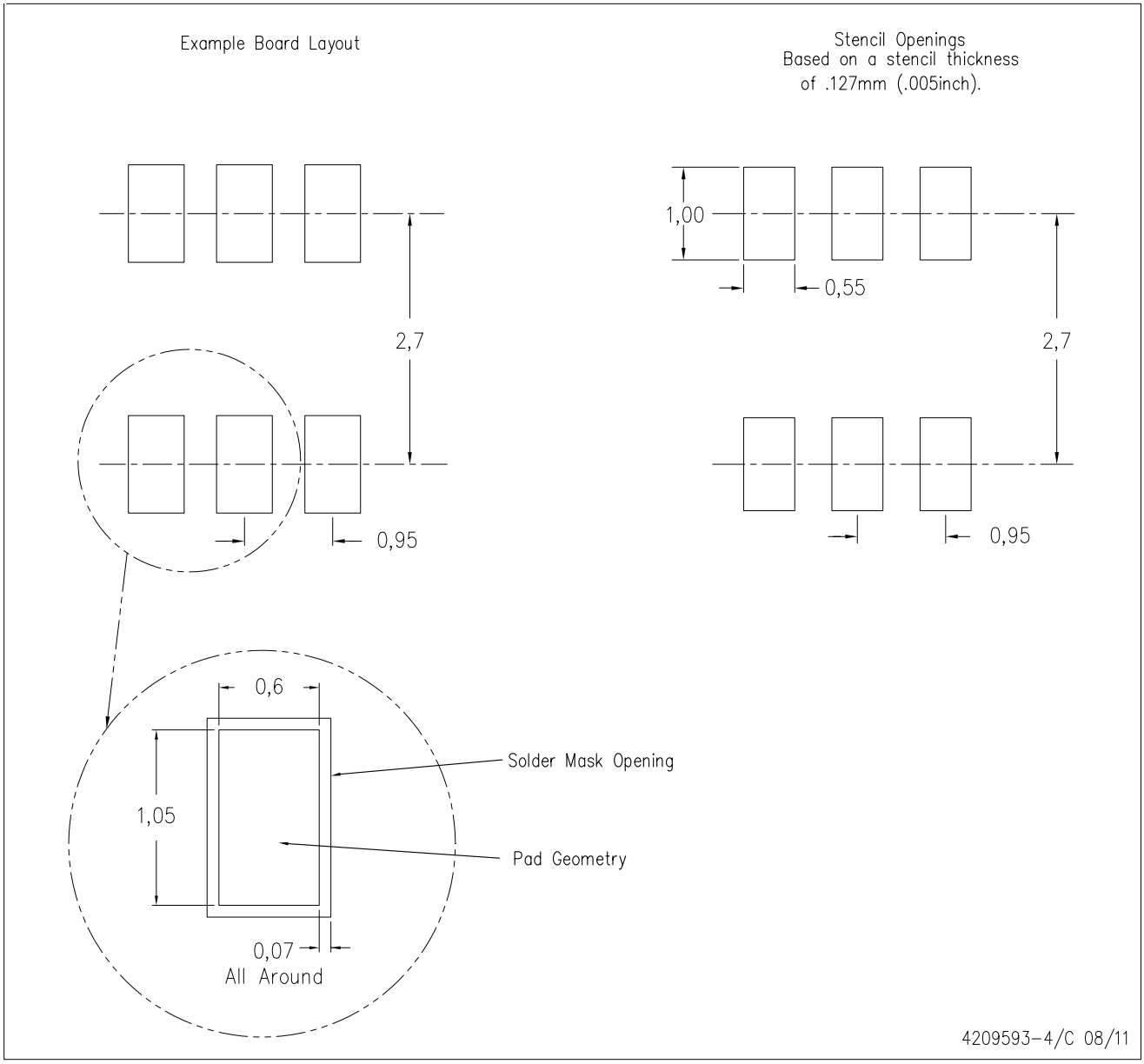
## DBV (R–PDSO–G6) PLASTIC SMALL–OUTLINE PACKAGE




4073253–5/K 03/2006

NOTES:
A. All linear dimensions are in millimeters.
B. This drawing is subject to change without notice.
C. Body dimensions do not include mold flash or protrusion. Mold flash and protrusion shall not exceed 0.15 per side.
D. Leads 1,2,3 may be wider than leads 4,5,6 for package orientation.
E. Falls within JEDEC MO–178 Variation AB, except minimum lead width.

DBV (R–PDSO–G6) PLASTIC SMALL OUTLINE




NOTES:
A. All linear dimensions are in millimeters.
B. This drawing is subject to change without notice.
C. Customers should place a note on the circuit board fabrication drawing not to alter the center solder mask defined pad.
D. Publication IPC–7351 is recommended for alternate designs.
E. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Example stencil design based on a 50% volumetric metal load solder paste. Refer to IPC–7525 for other stencil recommendations.

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